

### **A set of large time-step integration formulas**

**Kukk, Vello** ECS'03 : proceedings of the 4th Electronic Circuits and Systems Conference : September 11-12, 2003, Bratislava, Slovakia 2003 / p. 151-154 : ill

### **Automated design and diagnosis of electronic system based on description language representation**

Wawryn, Krzysztof; Drabarek, Jozef **BEC** : Baltic Electronics Conference : proceedings of the 4th Biennial Conference, October 9-14, 1994, Tallinn (Estonia). 2 1994 / p. 443-448 [https://www.ester.ee/record=b2150914\\*est](https://www.ester.ee/record=b2150914*est)

### **Automatic circuit partitioning for FPGAs**

**Krupnova, Helena**; Abbara, A.; Brasen, D.; Saucier, Gabriele **BEC'96** : the 5th Biennial Baltic Electronics Conference, October 7-11, 1996, Tallinn, Estonia : proceedings 1996 / p. 389-392: ill

### **Boole'i algebra kasutamine automaatikalülituste projekteerimisel : loengukonspekt**

**Agur, Ustus** 1972 [https://www.ester.ee/record=b1327567\\*est](https://www.ester.ee/record=b1327567*est)

### **Calculation of probabilistic testability measures for digital circuits with Structurally Synthesized BDDs**

**Jürimägi, Lembit; Ubar, Raimund-Johannes; Jenihhin, Maksim; Raik, Jaan** Microprocessors and microsystems 2020 / art. 103117, 12 p <https://doi.org/10.1016/j.micpro.2020.103117> [Journal metrics at Scopus](#) [Article at Scopus](#) [Journal metrics at WOS](#) [Article at WOS](#)

### **Chaos in electronic circuits**

Lindberg, Erik **BEC** : Baltic Electronics Conference : proceedings of the 4th Biennial Conference, October 9-14, 1994, Tallinn (Estonia). 1 1994 / p. 29-37: ill

### **Combinational fault simulation in sequential circuits**

**Ubar, Raimund-Johannes; Kõusaar, Jaak; Gorev, Maksim; Devadze, Sergei** 2015 IEEE International Symposium on Circuits and Systems : 24-27 May 2015, Lisboa, Portugal : [proceedings] 2015 / p. 2876-2879 : ill <https://doi.org/10.1109/ISCAS.2015.7169287> [Conference proceedings at Scopus](#) [Article at Scopus](#) [Article at WOS](#)

### **Complex delay fault reasoning with sequential 7-valued algebra**

**Kõusaar, Jaak; Ubar, Raimund-Johannes; Alekseev, Igor** 2015 16th Latin American Test Symposium (LATS 2015) : Puerto Vallarta, Mexico, 25-27 March 2015 2015 / [6] p. : ill <http://dx.doi.org/10.1109/LATW.2015.7102403>

### **Computational aspects of nodal method for simulation of electronic circuits**

**Laksberg, Edgar** 1983

### **Computer-aided examination of the P<sup>L</sup> current source and the behaviour of the P<sup>L</sup> flip-flop used in static memory cells**

**Rang, Toomas** Periodica polytechnica. Electrical engineering = Электротехника 1981 / p. 159-165 : joon [https://www.ester.ee/record=b1198855\\*est](https://www.ester.ee/record=b1198855*est) <https://pp.bme.hu/ee/article/view/4776/3881>

### **Conditional fault collapsing in digital circuits with shared structurally synthesized BDDs [Online resource]**

**Jürimägi, Lembit; Ubar, Raimund-Johannes** **BEC 2018** : 2018 16th Biennial Baltic Electronics Conference (BEC) : proceedings of the 16th Biennial Baltic Electronics Conference, October 8-10, 2018 2018 / 4 p. : ill <https://doi.org/10.1109/BEC.2018.8600967>

### **Critical path tracing based simulation of transition delay faults**

**Kõusaar, Jaak; Ubar, Raimund-Johannes; Devadze, Sergei; Raik, Jaan** 2014 17th Euromicro Conference on Digital System Design : DSD 2014 : 27-29 August 2014, Verona, Italy : proceedings 2014 / p. 108-113 : ill

### **Critical path tracing based simulation of transition delay faults**

**Kõusaar, Jaak; Ubar, Raimund-Johannes; Devadze, Sergei; Raik, Jaan** Proceedings of the 8th Annual Conference of the Estonian National Doctoral School in Information and Communication Technologies : December 5-6, 2014, Rakvere 2014 / p. 61-66 : ill

### **Defect-oriented library builder and hierarchical test generation**

Cibakova, Tatiana; Gramatova, Elena; Kuzmich, W.; Pleskacz, Witold A.; **Raik, Jaan; Ubar, Raimund-Johannes** IEEE Design and Diagnostics of Electronic Circuits and Systems - IEEE DDECS 2001 : Fourth International Workshop on IEEE Design and Diagnostics of Electronic Circuits and Systems : Győr, Hungary, April 18-20, 2001 2001 / p. 163-168 : ill

### **Defects, faults and fault models**

Gramatova, Elena; Fisherova, Maria; **Ubar, Raimund-Johannes**; Pleskacz, Witold A. Handbook of testing electronic systems 2005 / p. 26-96 : ill

### **Design error diagnosis in digital circuits with stuck-at fault model**

**Jutman, Artur; Ubar, Raimund-Johannes** Microelectronics reliability 2000 / p. 307-320 : ill [https://doi.org/10.1016/S0026-2714\(99\)00203-6](https://doi.org/10.1016/S0026-2714(99)00203-6)

### **Deterministic defect-oriented test generation for combinational circuits**

**Raik, Jaan; Ubar, Raimund-Johannes;** Sudbrock, Joachim; Kuzmich, Wieslaw; Pleskacz, Witold A. LATW 2005 : 6th IEEE Latin-American Test Workshop : March 30 - April 2, 2005, Salvador, Bahia, Brazil : [digest of papers] 2005 / p. 325-330 : ill

### **Diagnostics system for electronic circuits**

**Melentjev, Sergei** 11th International Symposium "Topical Problems in the Field of Electrical and Power Engineering." Doctoral School of Energy and Geotechnology II : Pärnu, Estonia, January 16-21, 2012 2012 / p. 192-194 : ill

### **Digitaalsüsteemide diagnostika**

**Ubar, Raimund-Johannes** 2005 [http://www.ester.ee/record=b2097071\\*est](http://www.ester.ee/record=b2097071*est)

### **Efficient at-speed interconnect BIST and diagnosis framework**

**Jutman, Artur** Informal Digest of Papers : 10 IEEE European Test Symposium : Tallinn, Estonia, May 22-25, 2005 2005 / p. 257-258 : ill [https://artiklid.elnet.ee/record=b1018804\\*est](https://artiklid.elnet.ee/record=b1018804*est)

### **Ein universeller Weg zur Automatisierung des Testentwurfs für digitale Objecte**

**Ubar, Raimund-Johannes;** Lohuaru, Tõnu Fehler in Automaten 1989 / S. 16-30 : Ill

### **Electronic circuits : examples for project based subject "Technologies of electronic products"**

**Sillakivi, Peeter; Tamm, Uljas** 2003 [https://www.ester.ee/record=b1828290\\*est](https://www.ester.ee/record=b1828290*est)

### **Elektronilülitused : näidiskeemid projektipõhilisele õppeainele "Elektrontoodete tehnoloogiad"**

2003 [https://www.ester.ee/record=b1828299\\*est](https://www.ester.ee/record=b1828299*est)

### **European Test Symposium : ETS 2005 : 22-25 May 2005, Tallinn, Estonia : proceedings**

Cantarella, JD 2005 [https://www.ester.ee/record=b2300865\\*est](https://www.ester.ee/record=b2300865*est)

### **Evolutionary approach to test generation for functional BIST**

Skobtsov, Y.A.; Ivanov, D.E.; Skobtsov, V.Y.; **Ubar, Raimund-Johannes; Raik, Jaan** Informal Digest of Papers : 10 IEEE European Test Symposium : Tallinn, Estonia, May 22-25, 2005 2005 / p. 151-155 : ill [https://artiklid.elnet.ee/record=b1018764\\*est](https://artiklid.elnet.ee/record=b1018764*est)

### **Exact parallel critical path fault tracing to speed-up fault simulation in sequential circuits**

**Kõusaar, Jaak; Ubar, Raimund-Johannes; Kostin, Sergei; Devadze, Sergei; Raik, Jaan** International journal of microelectronics and computer science 2018 / p. 9-18 <https://ijmcs.dmcsl.pl/web/guest/vol.-9-no.-1>  
[https://ijmcs.dmcsl.pl/documents/10630/345460/IJMCS\\_1\\_2018\\_2.pdf](https://ijmcs.dmcsl.pl/documents/10630/345460/IJMCS_1_2018_2.pdf)

### **Experimental performance validation of Z-source DC circuit breaker for high impedance faults**

Pogulaguntla, Aditya; Naik Banavath, Satish; **Chub, Andrii; Vinnikov, Dmitri;** Singh, Rajendra 2024 IEEE Sixth International Conference on DC Microgrids (ICDCM) 2024 / 5 p <https://doi.org/10.1109/ICDCM60322.2024.10664702>

### **Fast and efficient static compaction of test sequences using bipartite graph representations**

**Markus, Antti; Raik, Jaan; Ubar, Raimund-Johannes** ECS'99 : proceedings of the 2nd Electronic Circuits and Systems Conference : September 6-8, 1999, Bratislava, Slovakia 1999 / p. 17-20

### **Fast identification of true critical paths in sequential circuits**

**Ubar, Raimund-Johannes; Kostin, Sergei; Jenihhin, Maksim; Raik, Jaan; Jürimägi, Lembit** Microelectronics reliability 2018 / p. 252-261 : ill <https://doi.org/10.1016/j.microrel.2017.11.027> [Journal metrics at Scopus](#) [Article at Scopus](#) [Journal metrics at WOS](#) [Article at WOS](#)

### **Fault simulation with parallel exact critical path tracing in multiple core environment**

**Gorev, Maksim; Ubar, Raimund-Johannes; Devadze, Sergei** 2015 Design, Automation & Test in Europe Conference & Exhibition (DATE) : proceedings 2015 / p. 1180-1185 : ill

### **Handbook of testing electronic systems**

Novak, Ondrej; Gramatova, Elena; **Ubar, Raimund-Johannes; Jutman, Artur; Raik, Jaan** 2005 [https://www.ester.ee/record=b2102523\\*est](https://www.ester.ee/record=b2102523*est)

### **Hierarchical identification of NBTI-critical gates in nanoscale logic**

**Kostin, Sergei; Raik, Jaan; Ubar, Raimund-Johannes; Jenihhin, Maksim** LATW2014 : 15th IEEE Latin-American Test Workshop : Fortaleza, Brazil, March 12th-15th, 2014 2014 / [6] p. : ill

### **Hierarchical identification of untestable faults in sequential circuits**

**Raik, Jaan; Ubar, Raimund-Johannes; Krivenko, Anna; Kruus, Margus** 10th Euromicro Conference on Digital System Design Architectures, Methods and Tools, DSD 2007 : 29-31 August 2007, Lübeck, Germany : proceedings 2007 / p. 668-671 : ill <http://dx.doi.org/10.1109/DSD.2007.4341539>

**Identification and rejuvenation of NBTI-critical logic paths in nanoscale circuits**

**Jenihhin, Maksim**; Squillero, Giovanni; Tihomirov, Valentin; Kostin, Sergei; Raik, Jaan; Ubar, Raimund-Johannes Journal of electronic testing : theory and applications (JETTA) 2016 / p. 273-289 : ill <https://doi.org/10.1007/s10836-016-5589-x> [Journal metrics at Scopus](#) [Article at Scopus](#) [Journal metrics at WOS](#) [Article at WOS](#)

**Identification and rejuvenation of NBTI-critical paths in nanoscale logic circuits**

**Jenihhin, Maksim** 1st International Workshop on Reliability and Aging in Forthcoming Electronic Systems : May 28-29, 2015, Cluj-Napoca, Romania 2015 / [1] p

**Impulss-seadmed : laboratoorne töö nr. 5 : trigerid loogikaelementidel**

1986 [https://www.ester.ee/record=b1240931\\*est](https://www.ester.ee/record=b1240931*est)

**Impulss-seadmed : laboratoorne töö nr. 8 : lineaarpinge generaator**

1986 [https://www.ester.ee/record=b2618544\\*est](https://www.ester.ee/record=b2618544*est)

**Informal Digest of Papers : 10 IEEE European Test Symposium : Tallinn, Estonia, May 22-25, 2005**

2005 [https://www.ester.ee/record=b2055139\\*est](https://www.ester.ee/record=b2055139*est)

**Investigating defects in digital circuits by Boolean differential equations**

**Kruus, Helena**; Orasson, Elmet; Robal, Tarmo; Ubar, Raimund-Johannes The 4th International Conference "Distance Learning - Educational Sphere of XXI Century" (DLESC'04) 2004 / p. 432-435

**Low frequency acoustic method to measure the complex bulk modulus of porous materials**

Napolitano, Marialuisa; Di Giulio, Elio; **Auriemma, Fabio** The Journal of the Acoustical Society of America 2022 / art. 1545 <https://doi.org/10.1121/10.0009767> [Journal metrics at Scopus](#) [Article at Scopus](#) [Journal metrics at WOS](#) [Article at WOS](#)

**Low voltage 2-GHz GaAs transmitter circuit modules**

Kalajo, Sami; Kiraly, J.; Porra, Veikko BEC'96 : the 5th Biennial Baltic Electronics Conference, October 7-11, 1996, Tallinn, Estonia : proceedings 1996 / p. 167-170: ill

**Modeling and simulation of circuits with shared structurally synthesized BDDs**

**Ubar, Raimund-Johannes**; Jürimägi, Lembit; Raik, Jaan; Viies, Vladimir Microprocessors and microsystems 2017 / p. 56-61 : ill <https://doi.org/10.1016/j.micpro.2016.09.006> [Journal metrics at Scopus](#) [Article at Scopus](#) [Journal metrics at WOS](#) [Article at WOS](#)

**Modelling transients in oscillator circuits**

**Kukk, Vello** NDES'97, Moscow, June 26-27 : posters 1997 / p. 520-525: ill

**Multiple control fault testing in digital systems with high-level decision diagrams**

**Ubar, Raimund-Johannes**; Oyeniran, Adeboye Stephen 2016 IEEE International Conference on Automation, Quality and Testing, Robotics (AQTR) : THETA 20th edition : 19th-21st May, Cluj-Napoca, Romania : proceedings 2016 / [6] p. : ill <http://dx.doi.org/10.1109/AQTR.2016.7501287>

**Multiple fault analyses in logic circuits**

**Ubar, Raimund-Johannes** IFAC-Symposium Discrete Systems : Dresden, 14.-19. 3. 77 1977 / p. [?]

**Organ bio-impedance modelling with 3D mesh of equivalent circuits**

**Gordon, Rauno** Proceedings of the XII International Conference on Electrical Bioimpedance & the V Conference on Electrical Impedance Tomography : ICEB/EIT 2004 : June 20-24, 2004, Gdansk, Poland. Vol. 2 2004 / p. 715-718

**Overcoming convergence problems in simulation**

Aaltonen, Sakari BEC'96 : the 5th Biennial Baltic Electronics Conference, October 7-11, 1996, Tallinn, Estonia : proceedings 1996 / p. 273-276: ill

**Partition search for FSM low power synthesis**

**Sudnitsõn, Aleksander** Proceedings of the 4th International Conference "Computer-Aided Design of Discrete Devices" : CAD DD'2001 : Minsk, Belarus, 2001. Vol. 1 2001 / p. 44-49

**Performance optimization by Extended Peripheral Retiming**

Fehlauer, Erhard; Rülke, Steffen; Franke, Günter BEC : Baltic Electronics Conference : proceedings of the 4th Biennial Conference, October 9-14, 1994, Tallinn (Estonia). 2 1994 / p. 425-430: ill [https://www.ester.ee/record=b2150914\\*est](https://www.ester.ee/record=b2150914*est)

**Proceedings of the 2012 IEEE 15th International Symposium on Design and Diagnostics of Electronic Circuits & Systems (DDECS) : April 18-20, 2012 Tallinn, Estonia**

2012 [http://www.ester.ee/record=b2777270\\*est](http://www.ester.ee/record=b2777270*est)

**Product and manufacturing in electronics : supplementary material in the subject "Technologies of electronic circuits"**  
**Rang, Toomas** 2003 [https://www.ester.ee/record=b1766953\\*est](https://www.ester.ee/record=b1766953*est)

**Rejuvenation of nanoscale logic at NBTI-critical paths using evolutionary TPG**

Palermo, N.; **Tihomirov, Valentin**; Copetti, Thiago; **Jenihhin, Maksim**; **Raik, Jaan**; **Kostin, Sergei** 2015 16th Latin American Test Symposium (LATS 2015) : Puerto Vallarta, Mexico, 25-27 March 2015 2015 / [6] p. : ill  
<http://dx.doi.org/10.1109/LATW.2015.7102405>

**Research and training environment for digital design and test**

**Ubar, Raimund-Johannes**; Wuttke, Heinz-Dietrich Proceedings of the Eighth IASTED International Conference on Computers and Advanced Technology in Education : August 29-31, 2005, Oranjestad, Aruba 2005 / p. 232-237 : ill  
<https://ieeexplore.ieee.org/document/1408779>

**Reuse-dominated synthesis of electronic designs**

Conradi, Peter BEC : Baltic Electronics Conference : proceedings of the 4th Biennial Conference, October 9-14, 1994, Tallinn (Estonia). 2 1994 / p. 431-435: ill [https://www.ester.ee/record=b2150914\\*est](https://www.ester.ee/record=b2150914*est)

**Scalable algorithm for structural fault collapsing in digital circuits**

**Ubar, Raimund-Johannes**; **Jürimägi, Lembit**; **Orasson, Elmet**; **Raik, Jaan** 2015 IFIP/IEEE International Conference on Very Large Scale Integration (VLSI-SoC) : October 5-7, 2015, Daejeon, Korea 2015 / p. 171-176 : ill

**A scalable technique to identify true critical paths in sequential circuits**

**Ubar, Raimund-Johannes**; **Kostin, Sergei**; **Jenihhin, Maksim**; **Raik, Jaan** Proceedings 2017 IEEE 20th International Symposium on Design and Diagnostics of Electronic Circuit & Systems(DDECS) : April 19-21, 2017, Dresden, Germany 2017 / p. 152-157 : ill  
<https://ieeexplore.ieee.org/stamp/stamp.jsp?tp=&arnumber=7934553>

**7-valued algebra for transition delay fault analysis**

**Kõusaar, Jaak**; **Ubar, Raimund-Johannes** BEC 2014 : 2014 14th Biennial Baltic Electronics Conference : proceedings of the 14th Biennial Baltic Electronics Conference : Tallinn University of Technology, October 6-8, 2014, Tallinn, Estonia 2014 / p. 89-92 : ill

**Shared Structurally Synthesized BDDs for speeding-up parallel pattern simulation in digital circuits**

**Ubar, Raimund-Johannes**; **Jürimägi, Lembit**; **Raik, Jaan** 2015 Nordic Circuits and Systems Conference (NORCAS) : NORCHIP & International Symposium on System-on-Chip (SoC) : 1st IEEE NORCAS Conference : 26-28 October 2015, Oslo, Norway 2015 / [4] p. : ill <http://dx.doi.org/10.1109/NORCHIP.2015.7364406>

**SPICE-inspired fast gate-level computation of NBTI-induced delays in nanoscale logic**

**Kostin, Sergei**; **Raik, Jaan**; **Ubar, Raimund-Johannes**; **Jenihhin, Maksim** 2015 IEEE 18th International Symposium on Design and Diagnostics of Electronic Circuits & Systems DDECS 2015 : 22-24 April 2015, Belgrade, Serbia : proceedings 2015 / p. 223-228 : ill

**State of charge estimation for Li-ion batteries based on equivalent circuit diagrams and the application of a Kalman filter**

Rahmoun, Ahmad; Biechl, Helmuth; **Rosin, Argo** 12th International Symposium "Topical Problems in the Field of Electrical and Power Engineering." Doctoral School of Energy and Geotechnology II : Kuressaare, Estonia, June 11-16, 2012 2012 / p. 125-128 : ill

**Switched capacitor general immitance converter**

**Kängsep, Eiko**; **Kukk, Vello** BEC : Baltic Electronics Conference : proceedings of the 4th Biennial Conference, October 9-14, 1994, Tallinn (Estonia). 2 1994 / p. 483-486: ill [https://www.ester.ee/record=b2150914\\*est](https://www.ester.ee/record=b2150914*est)

**Symbolic test generation for hierarchically modeled digital systems**

**Zaugarov, Viktor** 1993 [https://www.ester.ee/record=b2090336\\*est](https://www.ester.ee/record=b2090336*est)

**Synthesis of hierarchically testable FSM networks**

Kasirova, Lilia; **Keevallik, Andres**; **Kruus, Margus** BEC : Baltic Electronics Conference : proceedings of the 4th Biennial Conference, October 9-14, 1994, Tallinn (Estonia). 1 1994 / p. 347-352: ill

**TCAD with device-circuit simulators for advanced process development, correlations between model parameters and optimization**

Bubennikov, Alexander N. BEC : Baltic Electronics Conference : proceedings of the 4th Biennial Conference, October 9-14, 1994, Tallinn (Estonia). 2 1994 / p. 517-522: ill [https://www.ester.ee/record=b2150914\\*est](https://www.ester.ee/record=b2150914*est)

**10th IEEE European Test Symposium**

**Ubar, Raimund-Johannes**; Prinetto, Paolo; **Raik, Jaan** IEEE journal of design & test of computers 2005 / p. 480-481 : phot  
<http://dx.doi.org/10.1109/MDT.2005.106>

**Testing tools**

**Jutman, Artur** Handbook of testing electronic systems 2005 / p. 361-365 : ill

## Testing tools

**Raik, Jaan** Handbook of testing electronic systems 2005 / p. 373-378 : ill

## A tool set for teaching design-for-testability of digital circuits

**Kostin, Sergei; Orasson, Elmet; Ubar, Raimund-Johannes** EWME 2016 : 11th European Workshop on Microelectronics Education : May 11-13, 2016, Southampton, UK 2016 / [6] p. : ill <https://doi.org/10.1109/EWME.2016.7496466>

## Transition delay fault simulation with parallel critical path back-tracing and 7-valued algebra

**Kõusaar, Jaak; Ubar, Raimund-Johannes; Devadze, Sergei; Raik, Jaan** Microprocessors and microsystems 2015 / p. 1130-1138 : ill <https://doi.org/10.1016/j.micpro.2015.05.003> [Journal metrics at Scopus](#) [Article at Scopus](#) [Journal metrics at WOS](#) [Article at WOS](#)

## Õkonoomsete negatiivse diferentsiaaltakistusega astmete ja elementide disainimine ja optimeerimine

**Tanilo, Rainer** 2005 [https://www.ester.ee/record=b2073482\\*est](https://www.ester.ee/record=b2073482*est)

## Генерирование тестов для цифровых схем при помощи модели альтернативных графов

**Ubar, Raimund-Johannes** Труды по электротехнике и автоматике : сборник статей. 14 1976 / с. 75-81 [https://www.ester.ee/record=b2190768\\*est](https://www.ester.ee/record=b2190768*est) <https://digikogu.taltech.ee/et/Item/aa35e320-87b1-405b-9cac-3b90c51867d1>

## Диалоговая система моделирования электронных схем "ПОИСК"

**Laksberg, Edgar; Nelus, K.; Ess, Viktor** Методы и устройства регистрации, передачи, обработки и представления информации 1986 / с. 63-68 : ил [https://www.ester.ee/record=b1232381\\*est](https://www.ester.ee/record=b1232381*est) <https://digikogu.taltech.ee/et/Item/56408e83-9c3f-4853-a7b7-7264cc685f1e>

## Единый подход к синтезу тестов цифровых схем и систем

**Ubar, Raimund-Johannes** Межреспубликанская школа-семинар по технической диагностике, 8-12 октября 1984 года : тезисы докладов 1984 / с. 75-81 : илл [https://www.ester.ee/record=b1237891\\*est](https://www.ester.ee/record=b1237891*est)

## Импульсные устройства : лабораторная работа No 5 : триггеры на логических элементах

1988 [https://www.ester.ee/record=b1224918\\*est](https://www.ester.ee/record=b1224918*est)

## Исследование алгоритмов преобразования и аппроксимации параметров линейных систем и цепей на ЭВМ : автореферат ... кандидата технических наук (05.13.01)

**Rüstern, Ennu** 1976 [https://www.ester.ee/record=b1301697\\*est](https://www.ester.ee/record=b1301697*est)

## Исследование алгоритмов преобразования и аппроксимации параметров линейных систем и цепей на ЭВМ : диссертация на соискание ученой степени кандидата технических наук

**Rüstern, Ennu** 1975 [https://www.ester.ee/record=b4630872\\*est](https://www.ester.ee/record=b4630872*est)

## О выборе варьируемых элементов при оптимизации электронных схем

**Laksberg, Edgar; Ess, Viktor** Труды по радиотехнике. 3 1976 / с. 3-8 : илл [https://www.ester.ee/record=b2190765\\*est](https://www.ester.ee/record=b2190765*est) <https://digikogu.taltech.ee/et/Item/051089c8-3240-47a7-84ae-2e65ba92e5fb>

## Об общей постановке задач тестовой диагностики цифровых схем

**Ubar, Raimund-Johannes** Труды по электротехнике и автоматике : сборник статей. 14 1976 / с. 69-73 [https://www.ester.ee/record=b2190768\\*est](https://www.ester.ee/record=b2190768*est) <https://digikogu.taltech.ee/et/Item/aa35e320-87b1-405b-9cac-3b90c51867d1>

## Организация тестовых экспериментов цифровых систем на основе модели альтернативных графов

**Lohuaru, Tõnu** Межреспубликанская школа-семинар по технической диагностике, 8-12 октября 1984 года : тезисы докладов 1984 / с. 47-52 [https://www.ester.ee/record=b1237891\\*est](https://www.ester.ee/record=b1237891*est)

## Применение алгебры Буля при проектировании схем автоматики : конспект лекций

**Agur, Ustus** 1974 [https://www.ester.ee/record=b1292481\\*est](https://www.ester.ee/record=b1292481*est)

## Руководство по применению пакета прикладных программ анализа и оптимизации электронных схем "ПОИСК"

1983 [https://www.ester.ee/record=b1271968\\*est](https://www.ester.ee/record=b1271968*est)

## Символьное моделирование линейных электронных схем

Сусану, Георгий; Кицул, Игорь 35 научная конференция студентов втузов Эстонии, Латвии, Литвы, Белоруссии и Молдовы : [Таллинн, 1991] : доклады. Секция математики [и др.] 1991 / с. 26-30: ил

## Структура и алгоритмы пакета прикладных программ анализа и оптимизации электронных схем "Поиск"

**Laksberg, Edgar; Ess, Viktor** Методы и средства обработки сигналов при наличии шумов 1982 / с. 31-38 [https://www.ester.ee/record=b1312255\\*est](https://www.ester.ee/record=b1312255*est) <https://www.etera.ee/zoom/121735/view?page=1&p=separate&search=true&tool=search>

Тестовая диагностика цифровых устройств : учебное пособие. II, Синтез и анализ тестов. Дешифрация  
диагностических экспериментов

Ubar, Raimund-Johannes 1981 [https://www.ester.ee/record=b1326795\\*est](https://www.ester.ee/record=b1326795*est)